


<b>Issue Classification</b> 	Application/Control No.	Applicant(s)/Patent under Reexamination	
	10/664,649	HEEG ET AL.	
	Examiner	Art Unit	
	Devin Hanan	3745	

ISSUE CLASSIFICATION										
ORIGINAL					CROSS REFERENCE(S)					
CLASS		SUBCLASS			CLASS	SUBCLASS (ONE SUBCLASS PER BLOCK)				
416		97R			415	115				
INTERNATIONAL CLASSIFICATION										
F	0	1	D	5/18						
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				/						
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<i>Devin Hanan 7/11/05</i> Devin Hanan 7/11/2005 (Assistant Examiner) (Date)	<i>Edward K. Look 7/11/05</i> EDWARD K. LOOK SUPERVISORY PATENT EXAMINER TECHNOLOGY CENTER 3700 (Patent Examiner) (Date)	Total Claims Allowed: 27  O.G. Print Claim(s) 1 O.G. Print Fig. 1
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<input type="checkbox"/> Claims renumbered in the same order as presented by applicant		<input type="checkbox"/> CPA		<input type="checkbox"/> T.D.		<input type="checkbox"/> R.1.47	
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